

POWER OF ATTORNEY BY ASSIGNEE OF ENTIRE INTEREST

Revocation of Power of Attorney with New Power of Attorney

NANYA TECHNOLOGY CORP., as assignee of record of the entire right, title and interest in each of the patent application(s) or patent(s) listed in the table of Attachment A, hereby revoke all powers of attorney previously given in each of the listed patent application(s) or patent(s) and appoint all practitioners associated with the Customer Number:

27765

as the attorney(s) or agent(s) to represent the undersigned before the United States Patent and Trademark Office (USPTO) in connection with any and all of the listed patent application(s) and patent(s).

Please recognize or change the correspondence address for the above-identified application to the address associated with the above-mentioned Customer Number.

Statement under 37 CFR 3.73(b)

I hereby state that, as required by 37 CFR 3.73(b)(1)(i), the documentary evidence of the chain of title from the original owner to the assignee was, or concurrently is being, submitted for recordation pursuant to 37 CFR 3.11. The chain of title is indicated in the table of Attachment A.

Pursuant to 37 CFR 3.71, I hereby state the prosecution of the listed application(s) or reexamination of the listed patent(s) is to be conducted to the exclusion of both the inventor(s) and previous assignee(s).

The undersigned is authorized to act on behalf of the assignee.

✓
Signature



✓
Date Sept. 8, 2009

Name

Jih Lien

Title

President

Attachment A

Appl. No.	Filing Date	Title	Chain of Title			
			No.	from	to	Reel/Frame No.
09/135,474	1998/08/17	PROCESS FOR MAKING AN ISOLATION STRUCTURE	1	LANE, RICHARD THAKUR, RANDHIR PS	MICRON TECHNOLOGY, INC.	010390/0415
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/911,580	2001/07/24	ISOLATION STRUCTURE AND PROCESS THEREFOR	1	LANE, RICHARD THAKUR, RANDHIR PS	MICRON TECHNOLOGY, INC.	010390/0415
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/291,127	1999/04/13	ELECTRODE AND CAPACITOR STRUCTURE FOR A	1	AGARWAL, VISHNU K.	MICRON TECHNOLOGY, INC.	009897/0668

		SEMICONDUCTOR DEVICE AND ASSOCIATED METHODS OF MANUFACTURE	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/654,997	2000/08/31	CAPACITOR AND ELECTRODE STRUCTURES FOR A SEMICONDUCTOR DEVICE	1	AGARWAL, VISHNU K.	MICRON TECHNOLOGY, INC.	011193/0819
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		COPPER METALLURGY IN INTEGRATED CIRCUITS	1	FARRAR, PAUL A.	MICRON TECHNOLOGY, INC.	009376/0238
09/128,859	1998/08/04		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		COPPER METALLURGY IN INTEGRATED CIRCUITS	1	FARRAR, PAUL A.	MICRON TECHNOLOGY, INC.	009376/0238
09/946,055	2001/09/04		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/033,064	1998/02/28	METHOD OF FORMING HIGH-K OXYGEN-CONTAINING DIELECTRIC LAYERS INCLUDING MANUFACTURE OF CAPACITORS AND DRAM CELLS	1	AL-SHAREEF, HUSAM N. DEBOER, SCOTT JEFFREY THAKUR, RANDHIR P. S.	MICRON TECHNOLOGY, INC.	009013/0121

			2	THAKUR, RANDHIR P.S.	MICRON TECHNOLOGY, INC.	009261/0355
			3	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	FORBES, LEONARD NOBLE, WENDELL P. CLOUD, EUGENE H.	MICRON TECHNOLOGY, INC.	010202/0223
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	FORBES, LEONARD NOBLE, WENDELL P. CLOUD, EUGENE H.	MICRON TECHNOLOGY, INC.	010202/0223
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	FORBES, LEONARD NOBLE, WENDELL P. CLOUD, EUGENE H.	MICRON TECHNOLOGY, INC.	010202/0223
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	FORBES, LEONARD NOBLE, WENDELL P. CLOUD, EUGENE H.	MICRON TECHNOLOGY, INC.	010202/0223
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

10/763,136	2004/01/22	PROGRAMMABLE MEMORY CELL USING CHARGE TRAPPING IN A GATE OXIDE	1	FORBES, LEONARD NOBLE, WENDELL P. CLOUD, EUGENE H.	MICRON TECHNOLOGY, INC.	010202/0223
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/389,294	1999/09/02	REDUCTION OF SHORTS AMONG ELECTRICAL CELLS FORMED ON A SEMICONDUCTOR SUBSTRATE	1	PING, ER-XUAN HUANG, YING	MICRON TECHNOLOGY, INC.	010219/0912
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		CIRCUIT AND METHOD FOR MEMORY DEVICE WITH DEFECT CURRENT ISOLATION	1	CASPER, STEPHEN L. PINNEY, DAVID KEETH, BRENT	MICRON TECHNOLOGY, INC.	008679/0825
08/911,667	1997/08/14		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

09/261,607	1999/02/26	CIRCUIT AND METHOD FOR MEMORY DEVICE WITH DEFECT CURRENT ISOLATION	1	CASPER, STEPHEN L. PINNEY, DAVID KEETH, BRENT	MICRON TECHNOLOGY, INC.	008679/0825
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/237,362	1999/01/26	CIRCUIT AND METHOD FOR MEMORY DEVICE WITH DEFECT CURRENT ISOLATION	1	CASPER, STEPHEN L. PINNEY, DAVID KEETH, BRENT	MICRON TECHNOLOGY, INC.	008679/0825
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/528,400	2000/03/20	Circuit and method for memory device with defect current isolation	1	CASPER, STEPHEN L. PINNEY, DAVID KEETH, BRENT	MICRON TECHNOLOGY, INC.	008679/0825
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

09/026,603	1998/02/20	TWISTED GLOBAL COLUMN DECODER	1	SHIRLEY, BRIAN M.	MICRON TECHNOLOGY, INC.	009012/0671
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		TWISTED GLOBAL COLUMN DECODER	1	SHIRLEY, BRIAN M.	MICRON TECHNOLOGY, INC.	009012/0671
09/362,076	1999/07/27		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		TWISTED GLOBAL COLUMN DECODER	1	SHIRLEY, BRIAN M.	MICRON TECHNOLOGY, INC.	009012/0671
09/583,439	2000/05/31		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		MID ARRAY ISOLATE CIRCUIT LAYOUT	1	MORGAN, DONALD M.	MICRON TECHNOLOGY, INC.	011385/0718
09/651,639	2000/08/30		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
10/229,555	2002/08/28	Mid-array isolate circuit layout and method	1	MORGAN, DONALD M.	MICRON TECHNOLOGY, INC.	011385/0718

			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/648,921	2000/08/25	Antifuse method to repair columns in a prefetched output memory architecture	1	MANNING, TROY A. MARTIN, CHRIS G. BATRA, SHUBNEESH MORGAN, DONALD M.	MICRON TECHNOLOGY, INC.	011062/0306
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
		Equilibration/pre-charge circuit for a memory device	1	MERRITT, TODD A. INGALLS, CHARLES L. RAAD, GEORGE B.	MICRON TECHNOLOGY, INC.	011042/0154
09/645,577	2000/08/25		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

08/838,010	1997/04/22	SELF-TEST OF A MEMORY DEVICE	1	BEFFA, RAY J. WALLER, WILLIAM K. NEVILL, LELAND R. FARNWORTH, WARREN M. CLOUD, EUGENE H.	MICRON TECHNOLOGY, INC.	008537/0289
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
08/886,195	1997/07/01	METHOD AND APPARATUS FOR MEMORY ARRAY COMPRESSED DATA TESTING	1	KEETH, BRENT MANNING, TROY A. MARTIN, CHRIS G. PIERCE, KIM M. FISTER, WALLACE E. RYAN, KEVIN J. LEE, TERRY R. PEARSON, MIKE VOSHELL, THOMAS W.	MICRON TECHNOLOGY, INC.	009373/0058

			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	SHER, JOSEPH C. BLODGETT, GREG A.	MICRON TECHNOLOGY, INC.	008657/0259
08/906,754	1997/08/05	MEMORY REPAIR	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	MERRIT, TODD A. VAN HEEL, NICK	MICRON TECHNOLOGY, INC.	010548/0094
			2	HEEL, NICK VAN	MICRON TECHNOLOGY, INC.	011803/0738
			3	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	HU, YONGJUN	Micron Technology, Inc.	008777/0373
10/003,522	2001/10/31	ANTIREFLECTIVE COATING LAYER	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/352,352	1999/07/13	TEST AND OBSERVE MODE FOR EMBEDDED MEMORY				

09/631,264	2000/08/02	PHOTOLITHOGRAPHY METHOD USING AN ANTIREFLECTIVE COATING	1	HU, YONGJUN	Micron Technology, Inc.	008777/0373
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
09/476,558	2000/01/03	ANTIREFLECTIVE COATING LAYER	1	HU, YONGJUN	Micron Technology, Inc.	008777/0373
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
10/233,997	2002/08/29	DRIVING A DRAM SENSE AMPLIFIER HAVING LOW THRESHOLD VOLTAGE PMOS TRANSISTORS	1	JOO, YANGSUNG	MICRON TECHNOLOGY, INC.	013267/0389
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
10/783,976	2004/02/20	DRIVING A DRAM SENSE AMPLIFIER HAVING LOW THRESHOLD VOLTAGE PMOS TRANSISTORS	1	JOO, YANGSUNG	MICRON TECHNOLOGY, INC.	013267/0389
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
10/696,971	2003/10/30	Data compression read mode for memory testing	1	NASO, GIOVANNI	MICRON TECHNOLOGY, INC.	014659/0206

			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	MERRITT, TODD A. THOMPSON, J. WAYNE	MICRON TECHNOLOGY, INC.	011693/0081
09/805,913	2001/03/15		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	MARR, KENNETH W. PORTER, JOHN D.	MICRON TECHNOLOGY, INC.	013251/0264
10/230,928	2002/08/29		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	MARR, KENNETH W. PORTER, JOHN D.	MICRON TECHNOLOGY, INC.	013251/0264
10/931,366	2004/08/31		2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

10/231,389	2002/08/29	WORD LINE DRIVER FOR NEGATIVE VOLTAGE	1	KIRSCH, HOWARD KIM, TAE HYOUNG INGALLS, CHARLES L.	MICRON TECHNOLOGY, INC.	013255/0858
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
10/232,953	2002/08/29	SYSTEM AND METHOD FOR NEGATIVE WORD LINE DRIVER CIRCUIT	1	KIM, TAE HYOUNG VO, HUY BLODGETT, GREG	MICRON TECHNOLOGY, INC.	013543/0899
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
10/860,881	2004/06/03	SYSTEM AND METHOD FOR NEGATIVE WORD LINE DRIVER CIRCUIT	1	KIM, TAE HYOUNG VO, HUY BLODGETT, GREG	MICRON TECHNOLOGY, INC.	013543/0899
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

08/950,319	1997/10/14	POROUS SILICON OXYCARBIDE INTEGRATED CIRCUIT INSULATOR	1	AHN, KIE Y. FORBES, LEONARD	MICRON TECHNOLOGY, INC.	008784/0988
			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	AHN, KIE Y. FORBES, LEONARD	MICRON TECHNOLOGY, INC.	008784/0988
09/517,029	2000/03/02	Porous silicon oxycarbide integrated circuit insulator	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	AHN, KIE Y. FORBES, LEONARD	MICRON TECHNOLOGY, INC.	008784/0988
09/909,532	2001/07/20	POROUS SILICON OXYCARBIDE INTEGRATED CIRCUIT INSULATOR	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	AHN, KIE Y. FORBES, LEONARD	MICRON TECHNOLOGY, INC.	008784/0988
10/083,051	2002/02/26	POROUS SILICON OXYCARBIDE INTEGRATED CIRCUIT INSULATOR	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

08/102,908	1993/08/06	METHOD FOR OPTIMIZING THERMAL BUDGETS IN FABRICATING SEMICONDUCTORS	1	THAKUR, RANDHIR P.S. GONZALEZ, FERNANDO	MICRON SEMICONDUCTOR, INC.	006665/0347
			2	MICRON SEMICONDUCTOR, INC.	Micron Technology, Inc.	attached
			3	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
08/427,941	1995/04/25	METHOD FOR OPTIMIZING THERMAL BUDGETS IN FABRICATING SEMICONDUCTORS	1	THAKUR, RANDHIR P.S.	MICRON SEMICONDUCTOR, INC.	007460/0835
			2	MICRON SEMICONDUCTOR, INC.	MICRON TECHNOLOGY INC.	009187/0739
			3	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
08/559,511	1995/11/15	METHOD FOR OPTIMIZING THERMAL BUDGETS IN FABRICATING SEMICONDUCTORS	1	THAKUR, RANDHIR P.S. GONZALEZ, FERNANDO	MICRON TECHNOLOGY, INC.	007811/0575
			2	THAKUR, RANDHIR P.S. GONZALEZ, FERNANDO	MICRON TECHNOLOGY, INC., A DELAWARE CORP	008235/0516

			3	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	KIRSCH, HOWARD C.	MICRON TECHNOLOGY, INC.	013256/0297
10/231,626	2002/08/29	METHOD AND CIRCUIT FOR REDUCING DRAM REFRESH POWER BY REDUCING ACCESS TRANSISTOR SUB THRESHOLD LEAKAGE	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	KIRSCH, HOWARD C.	MICRON TECHNOLOGY, INC.	013256/0297
11/040,959	2005/01/19	METHOD AND CIRCUIT FOR REDUCING DRAM REFRESH POWER BY REDUCING ACCESS TRANSISTOR SUB THRESHOLD LEAKAGE	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	JOO, YANGSUNG PINNEY, DAVID L. BROWN, JASON	MICRON TECHNOLOGY, INC.	015741/0152
10/926,357	2004/08/26	DUAL STAGE DRAM MEMORY EQUALIZATION	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
08/666,617	1996/06/18	Voltage generator for antifuse programming	1	SHER, JOSEPH C.	MICRON TECHNOLOGY, INC.	008063/0562

			2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation
			1	FORBES, LEONARD	MICRON TECHNOLOGY, INC.	011067/0527
09/651,630	2000/08/30	Clock-delayed pseudo-nmos domino logic	2	Micron Technology, Inc.	NANYA TECHNOLOGY CORP.	attached and concurrently submitted for recordation

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ASSIGNMENT

WHEREAS, Micron Technology, Inc., a corporation organized and existing under the laws of Delaware ("ASSIGNOR"), owns certain patent applications and/or registrations, as set forth in Attachment 1 attached hereto and incorporated herein by this reference ("PATENTS"); and

WHEREAS, Nanya Technology Corporation (南亞科技股份有限公司), a company incorporated under the laws of the Republic of China ("ASSIGNEE"), desires to acquire all of the right, title and interest of ASSIGNOR in, to and under the PATENTS;

WHEREAS, ASSIGNOR and ASSIGNEE have entered into a certain Patent Assignment Agreement, dated June 6, 2008 assigning, all of ASSIGNOR's right, title and interest in and to the PATENTS from ASSIGNOR to ASSIGNEE upon the terms and subject to the conditions set for the in the Patent Assignment Agreement;

NOW, THEREFORE, in consideration of the sum of One Dollar (\$1.00) and other good and valuable consideration from ASSIGNEE to ASSIGNOR, the receipt and sufficiency of which hereby is acknowledged, ASSIGNOR does hereby sell, assign, transfer and convey unto ASSIGNEE all of ASSIGNOR's right, title and interest in and to the PATENTS, including all rights to causes of action and remedies related thereto (including, the right to sue for past, present or future infringement related to the foregoing) upon the terms and subject to the conditions set forth in the Patent Assignment Agreement;

IN WITNESS WHEREOF, ASSIGNOR has caused this Assignment to be duly executed by an authorized officer on this 5th day of June, 2009.

By:

Name:

Title:

Roderic W. Lewis
Roderic W. Lewis
V. P. of Legal Affairs

STATE OF

Idaho

)

) ss.

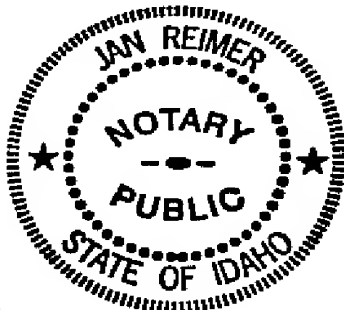
COUNTY OF

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On June 5, 2009, before me, the undersigned notary public in and for said County and State, personally appeared Roderic W. Lewis, personally known to me to be the person(s) whose name is subscribed to the above instrument and acknowledged to me that he executed the same in his authorized capacity and that, by his signature on the instrument, the entity upon behalf of which he acted executed the instrument.

WITNESS my hand and official seal.



Jan Reimer

My commission expires on

9/11/2013

ATTACHMENT 1

PATENTS

SERIAL NUMBER OR REGISTRATION NUMBER	FILING DATE
6265282	8/17/1998
6414364	7/24/2001
6218256	4/13/1999
6346746	8/31/2000
6284656	8/4/1998
6614099	9/4/2001
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6373290	8/30/2000